

# Thick-wire ETI Growth under Dielectric Coatings

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# Motivation (MagLIF)

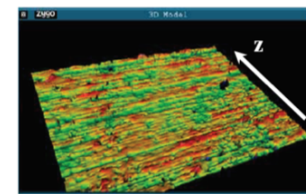
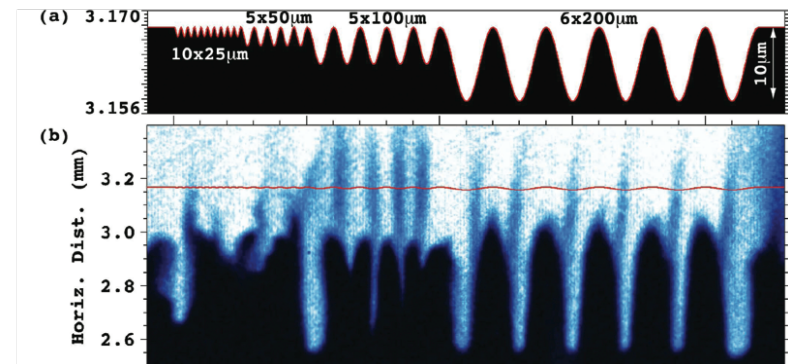
- In a z-pinch, electrical currents are axially driven through conductors (often axis-symmetric annuli called liners).
- Self-generated magnetic fields radially compress (via  $\vec{j} \times \vec{B}$  forces) conductive material (and entrained matter) into a high energy-density state on axis.
- MagLIF<sup>1</sup> involves filling the liner with DT fuel and compressing it to conditions suitable for fusion.
- When the low-density magnetic field accelerates the high-density metal, they slip through each-other in what is called the Magneto-Rayleigh Taylor (MRT) instability.
- MRT sections the liner and disrupts compression. Sea monster of nuclear fusion. Represents a significant MagLIF threat.

<sup>1</sup>Slutz (2010)

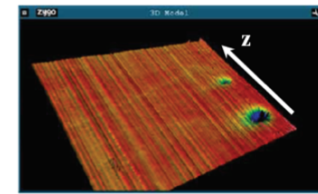
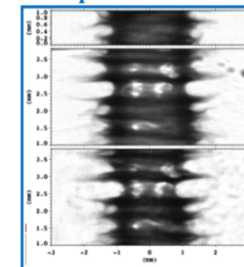


# The MRT Instability

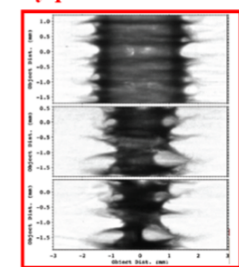
- You would expect to see the same ratio between perturbations if growth were linear to initial perturbations.<sup>1</sup>
- Highly azimuthally correlated but surprisingly not with residual lathe structure.<sup>2</sup>
- So therefore everybody looked for another, earlier instability that generates azimuthal density perturbations capable of 'seeding' the liner for MRT.



Standard process → 50 nm RMS



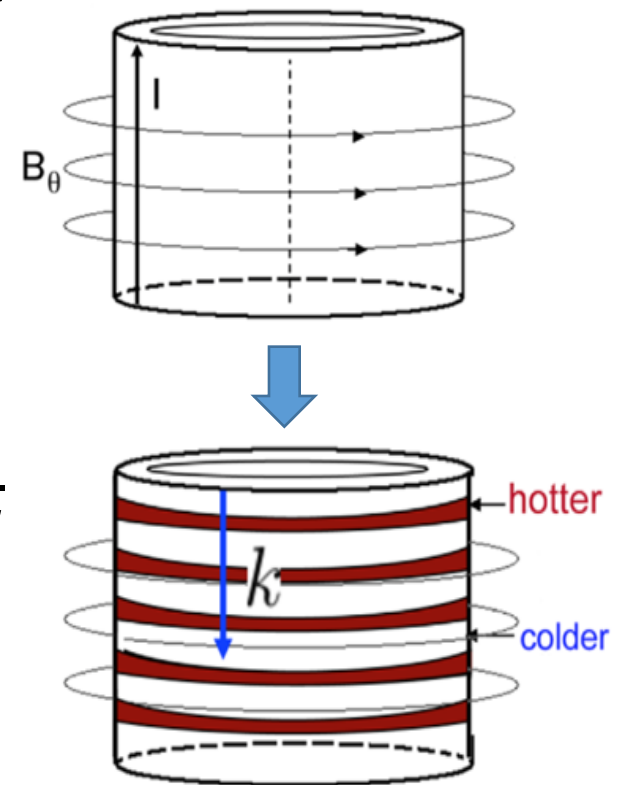
Axially polished → 50 nm RMS



<sup>1</sup>Sinars (2010) <sup>2</sup>McBride (2012)

# Electro-Thermal Instability (ETI) Origins

- Suspicion came to rest on fast thermal instabilities that grow after melt.<sup>1</sup> Striation vs filamentation. Strata more readily couple to MRT than filaments.
- If:  $c_v \rho \frac{\partial T}{\partial t} = \eta j^2$  and  $\eta = \eta_0 + \frac{\partial \eta}{\partial T} T$
- Then:  $\delta T = \delta T_0 e^{\gamma t}$  where  $\gamma = \frac{j^2}{c_v \rho} \frac{\partial \eta}{\partial T}$
- The hypothesized evolution is  $\delta T \rightarrow \delta p \rightarrow \delta \rho$ , which carries the imprinted azimuthal symmetry into the compression phase.



<sup>1</sup>Peterson (2012)

# Thin-Wire ETI is analytically treatable:

- Where  $T^*$  depends quadratically on  $\gamma$  and contains EOS parameters specific to material.
- The **hydro version** predicts that  $\delta T \sim i \delta \rho$ , so troughs are hotter than peaks.<sup>1</sup>
- **This term** is also called the electrochoric instability (ECI).<sup>2</sup>
- ETI is predicted to grow fastest when conductor is a liquid-vapor bi-phase. If you can keep material out of this regime it is less dangerous.

Without  
Hydrodynamics

$$\gamma = \frac{j^2 \frac{\partial \eta}{\partial T} - k_z^2 \kappa}{c_v \rho}$$

$$\lambda_{min} = \frac{2\pi}{j} \sqrt{\kappa \left( \frac{\partial \eta}{\partial T} \right)^{-1}}$$

With  
Hydrodynamics

$$\gamma = \frac{j^2 \frac{\partial \eta}{\partial T} + \frac{\rho}{T^*} \left( c_v \frac{\partial T}{\partial t} - j^2 \frac{\partial \eta}{\partial \rho} \right) - k_z^2 \kappa}{c_v \rho + \frac{p}{T^*}}$$

<sup>1</sup>Oreshkin (2008)

<sup>2</sup>Pecover (2015)



# Application of EOS tables w/out hydro to thin-wire case implies ETI wavelengths grow in time.

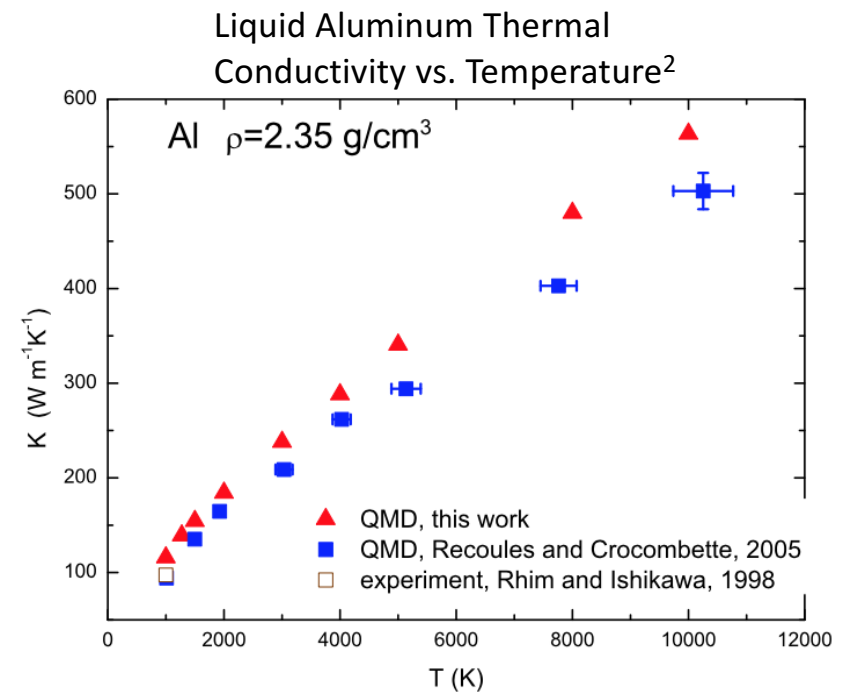
- The Wiedemann-Franz relation,  $\frac{\eta\kappa}{T} = \frac{\pi^2 k_b^2}{3e^2}$  is suitable for  $\frac{\partial\eta}{\partial T}$  in the thin wire case.<sup>1</sup>

$$\longrightarrow \lambda_{min} = \frac{e\kappa}{jk_b} \sqrt{12}$$

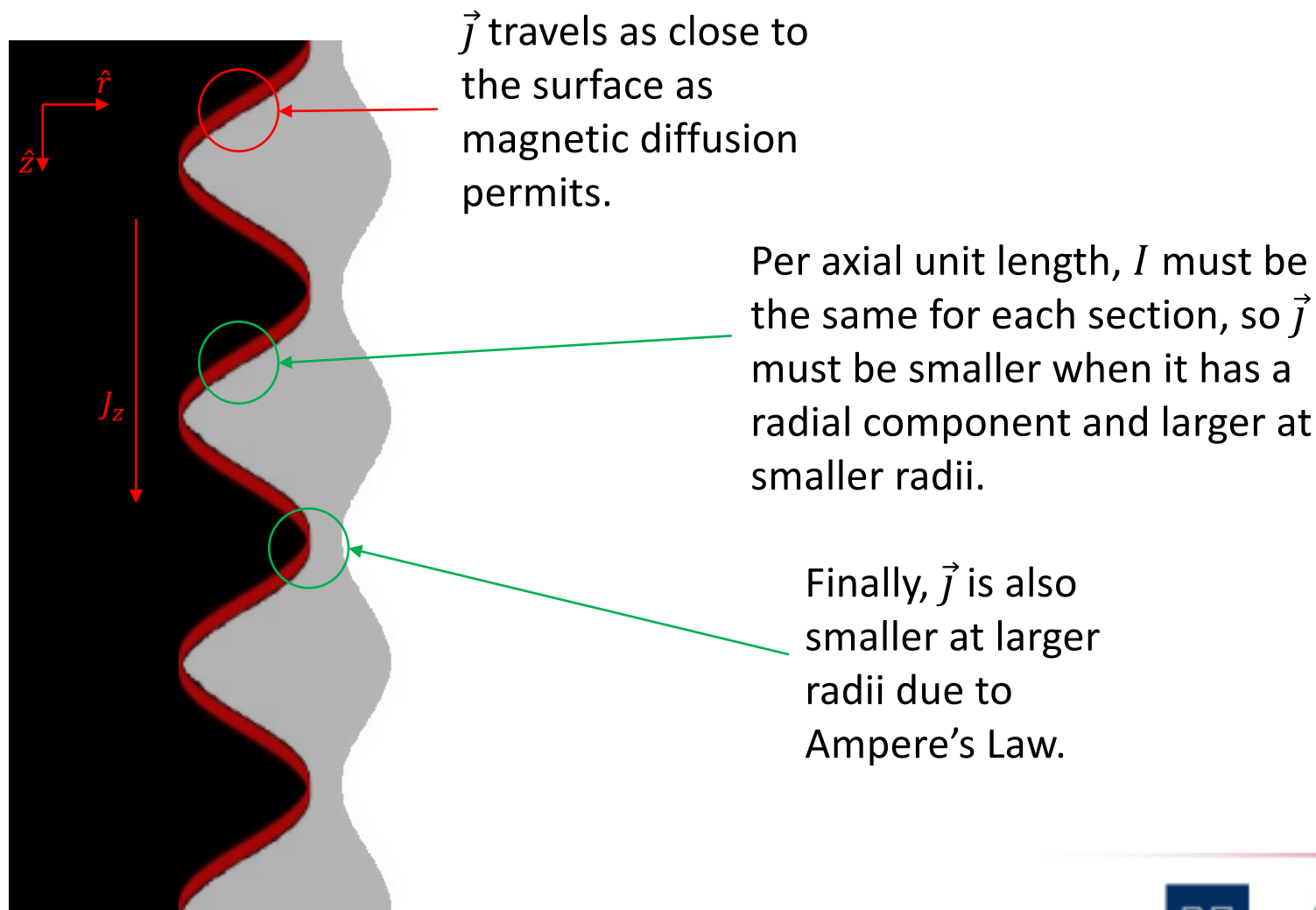
- On the surface:  $\frac{\partial T}{\partial t} > 0$  means that  $\frac{\partial\kappa}{\partial t} > 0$ , and since  $\frac{\partial j}{\partial t} < 0$ :

$$\longrightarrow \frac{\partial\lambda_{min}}{\partial t} > 0$$

<sup>1</sup>Recoules (2005) <sup>2</sup>Knyazev (2013)

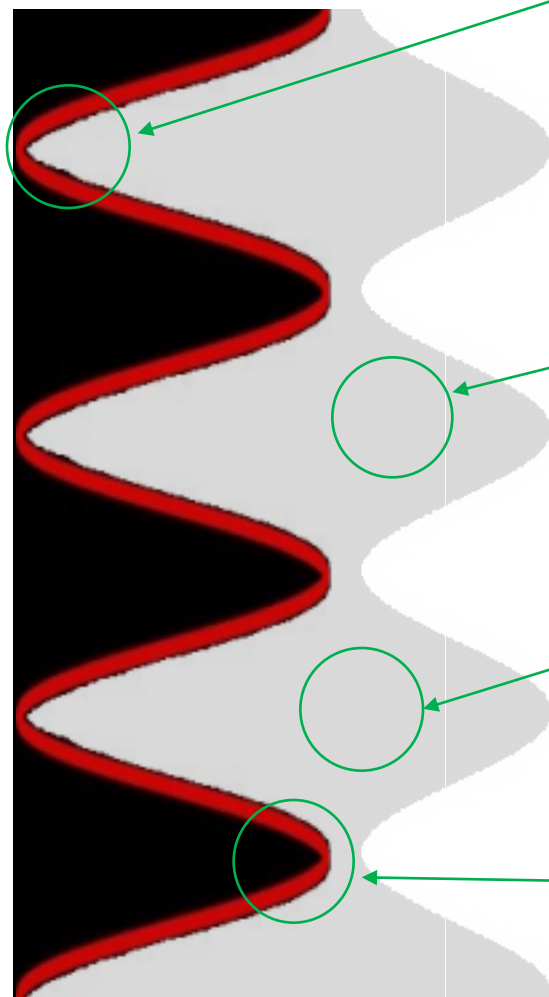


Given an initial axisymmetric perturbation in  $\rho$  or  $\eta$  (i.e. consider 2-D thick ETI with hydro)





# ETI/ECI drives deepening axisymmetric grooves



Since  $\vec{j}$  is larger here,  $\eta \vec{j}^2$  is larger. Consequently, the temperature grows faster and results in (for  $\partial\eta/\partial T > 0$ ) more resistive and if after melt (since  $\partial\eta/\partial\rho < 0$ ) less dense material.

Less dense material means flux penetration depth is greater, and  $\vec{j}$  is larger (i.e.  $\vec{j}$  'dips' inwards to take a lower resistance path (even if inductance goes up marginally))

Since  $v_A^2 \sim \rho^{-1}$ , low density material can correlate most quickly, so w/out axisymmetry, ' $\vec{B}$ -hernias' azimuthally correlate fastest here.

Result is large-amplitude high-density perturbations suitable for MRT initialization.





# Dielectric Coatings suppress $\delta\dot{\rho}$

- Dielectric coatings are theorized to constraining mass redistribution and therefore MRT seeds.

$$\gamma = \frac{j^2 \frac{\partial \eta}{\partial T} + \frac{\rho}{T^*} \left( c_v \frac{\partial T}{\partial t} - j^2 \frac{\partial \eta}{\partial \rho} \right) - k_z^2 \kappa}{c_v \rho + \frac{p}{T^*}}$$

- Coatings affect MRT in two intertwined but distinct ways:
  - Dielectric inhibits  $\delta\dot{\rho}$ , suppressing the **ETI growth rate dependence on  $\frac{\partial \eta}{\partial \rho}$** , the so-called Electrochoric Instability (ECI).<sup>2</sup>
  - Dielectric limits MRT initialization amplitudes by constraining  $\delta p \rightarrow \delta \rho$  evolution independent of ETI/ECI growth rates.

<sup>1</sup>Oreshkin (2008) & Peterson (2012, 2013, 2014) <sup>2</sup>Pecover (2015)





# Important unknowns remain

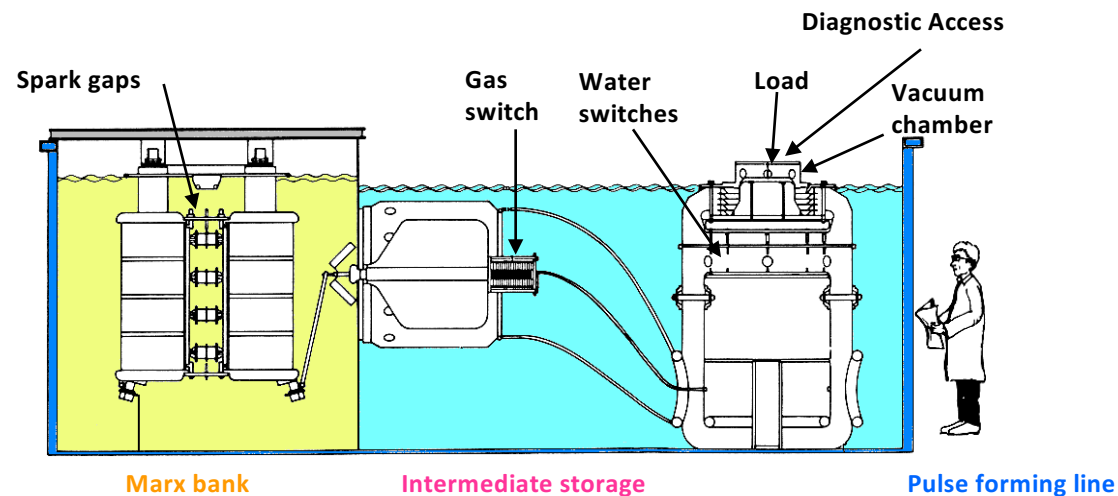
- Thin wire experiments demonstrate that dielectric overcoats suppress plasma formation, inhibiting the current from shunting and permitting greater energy deposition in the wire.<sup>1</sup> Analytic thin-wire theory implies that greater energy deposition rates mean *faster* instability growth, so must the theory be inapplicable for the thick-wire case since an applied dielectric reduces instabilities?<sup>2</sup>
- Oreshkin and Pecover argue in opposition whether conductor strength is relevant for ETI growth.
- Experiments have verified that on Z, the dielectric carries sufficient current to implode with the liner,<sup>2</sup> but simulations do not predict an imploding dielectric.<sup>3</sup> This disparity motivated the experiments we have performed.

<sup>1</sup> Sinars (2010b) & Sarkisov (2004) <sup>2</sup>Awe (2016) & Peterson (2014) <sup>3</sup>Peterson (2014).

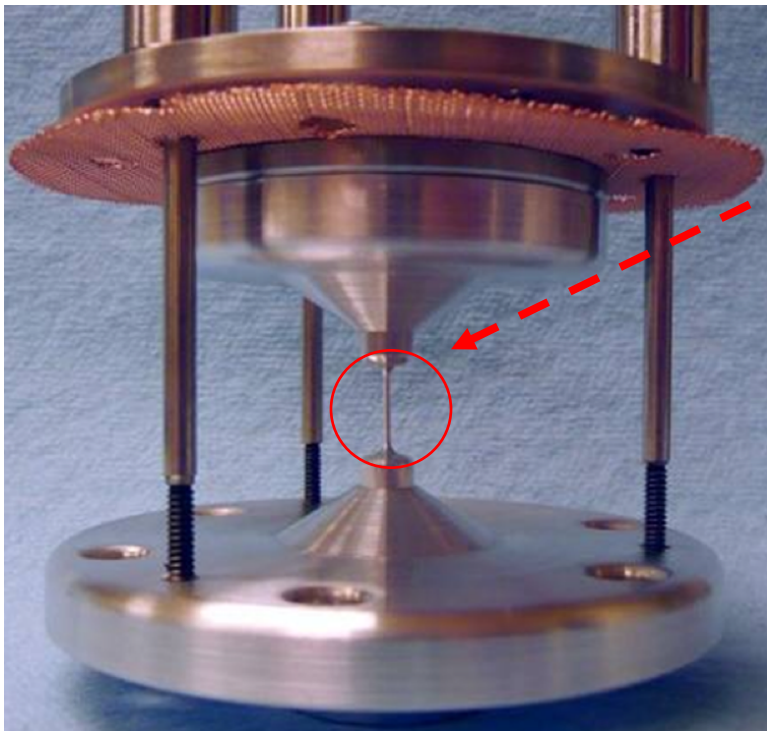


# Zebra Pulsed Power Accelerator

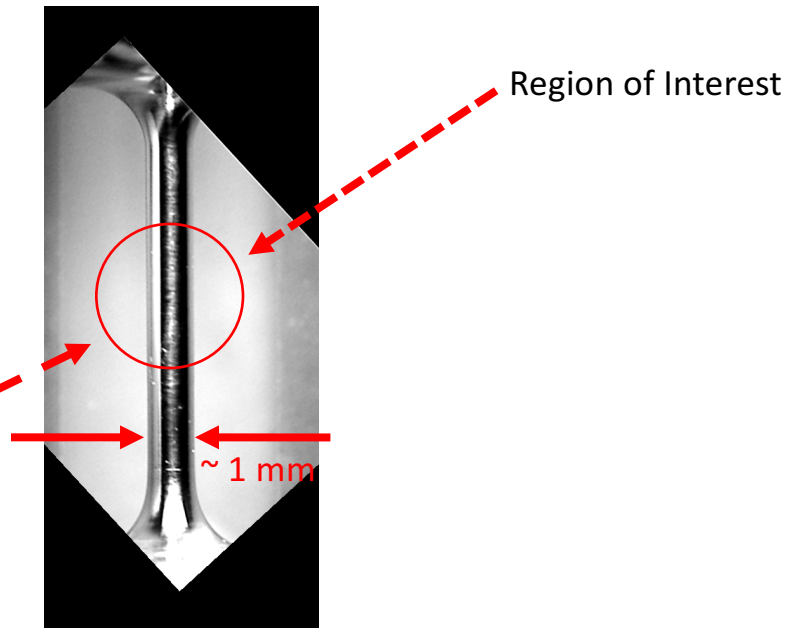
- Zebra is a Marx-configured 1 MA driver at UNR. Chamber is return can, so optical ports are >13" from TCC.
- Bank stores 150 kJ, and delivers in 100 ns via a transmission impedance of  $1.9\ \Omega$  to our  $\sim m\Omega$  loads. Given the impedance mismatch, small variations in load resistance do not affect accelerator performance.
- We define 500 kA to be at 100 ns: Zebra  $\rightarrow$  11 kA/ns ( $\sim$  3-8 T/ns) linear current until 0.9 MA.



# Load hardware reproducibly mitigates non-thermal breakdown



Cathode

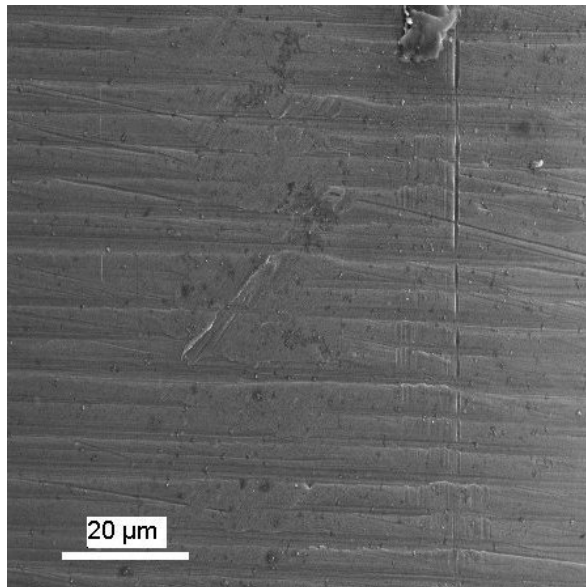


Buried knife-edge contacts mitigate arcing/break oxide layer, and smooth electrode transitions inhibit avalanche breakdown.

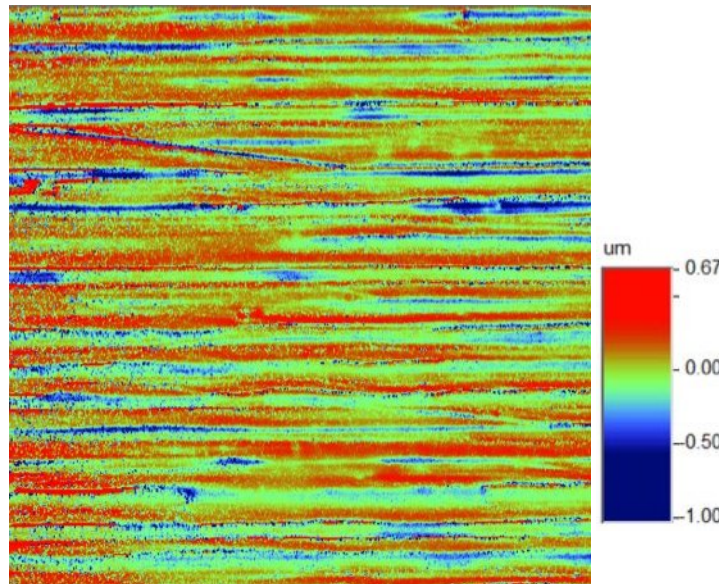
# Tested Load Types and Surface Features well characterized

(CM) Eleven Conventionally Machined Pulse-Oxide Electropolished  $\varnothing 974 \pm 9 \mu m$  :: Machining is consistently  $5.1 \pm 0.2 \mu m$   
(CH) Five CM then had  $70 \pm 5 \mu m$  Parylene-N Chemical Vapor Deposited

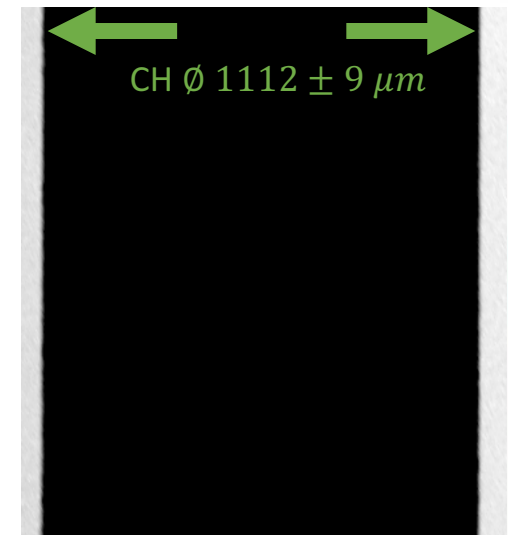
CM Scanning Electron Micrograph SE



CM White Light Interferogram



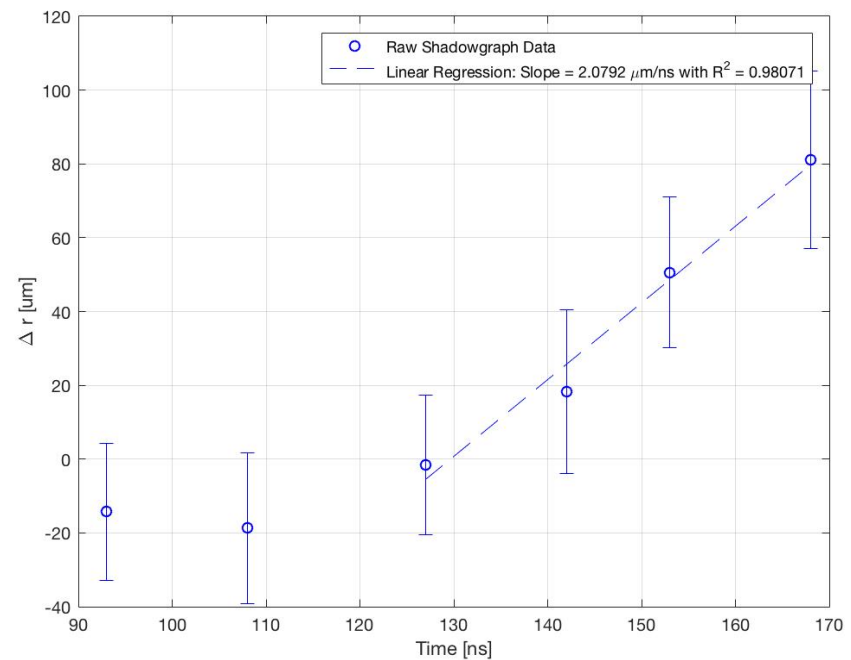
Preshot Backlit Optical Micrograph





# Shadowgraph Diameters -> Expansion

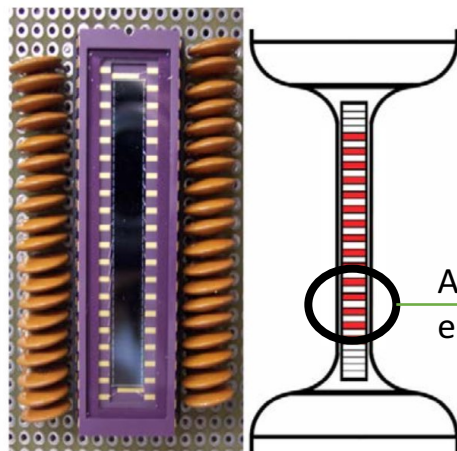
- Experimental CH expansion speed is  $2.1 \pm 0.27 \mu\text{m/ns}$ .  $\pm$  is due to linear regression fitness.
- Expansion speeds have previously been measured for **uncoated aluminum** are  $3 \mu\text{m/ns}$  using the same method.<sup>1</sup>
- This reduction in expansion speed is consistent with hydrodynamic tamping of expanding low-density vapor.



<sup>1</sup> Awe, T. Dissertation pg. 209.

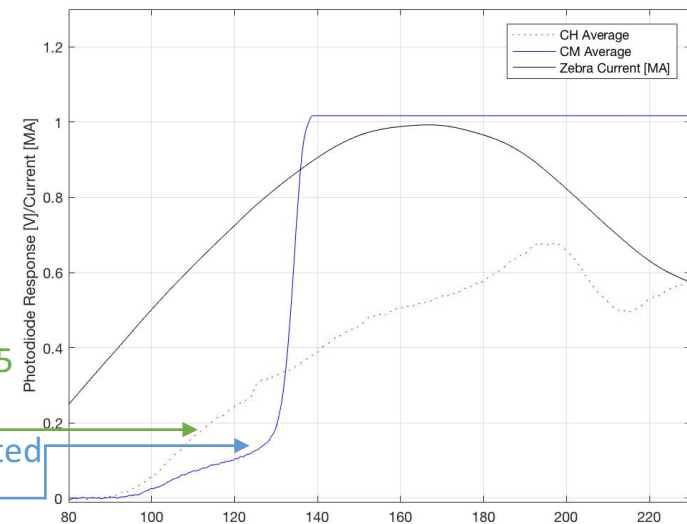
# VIS Radiometry for CH Loads -> initially hotter, then cooler emitter

- Literature<sup>1,2</sup> suggests breakdown is correlated with a rapid increase in VIS emissions, which we see for uncoated (~140 ns) but not coated loads. Available implication is plasma doesn't form.
- During the 'ramp' section of 95-125 ns, the ratio of coated to uncoated emissions is a nearly constant  $2.7 \pm 0.1$  (taking into account  $T_r = 85\%$ )
- That the ratio is  $> 1$  is consistent with thin-wire experiments in that the dielectric overcoat increases energy deposition (therefore radiance).



Avg. across 4  
elements

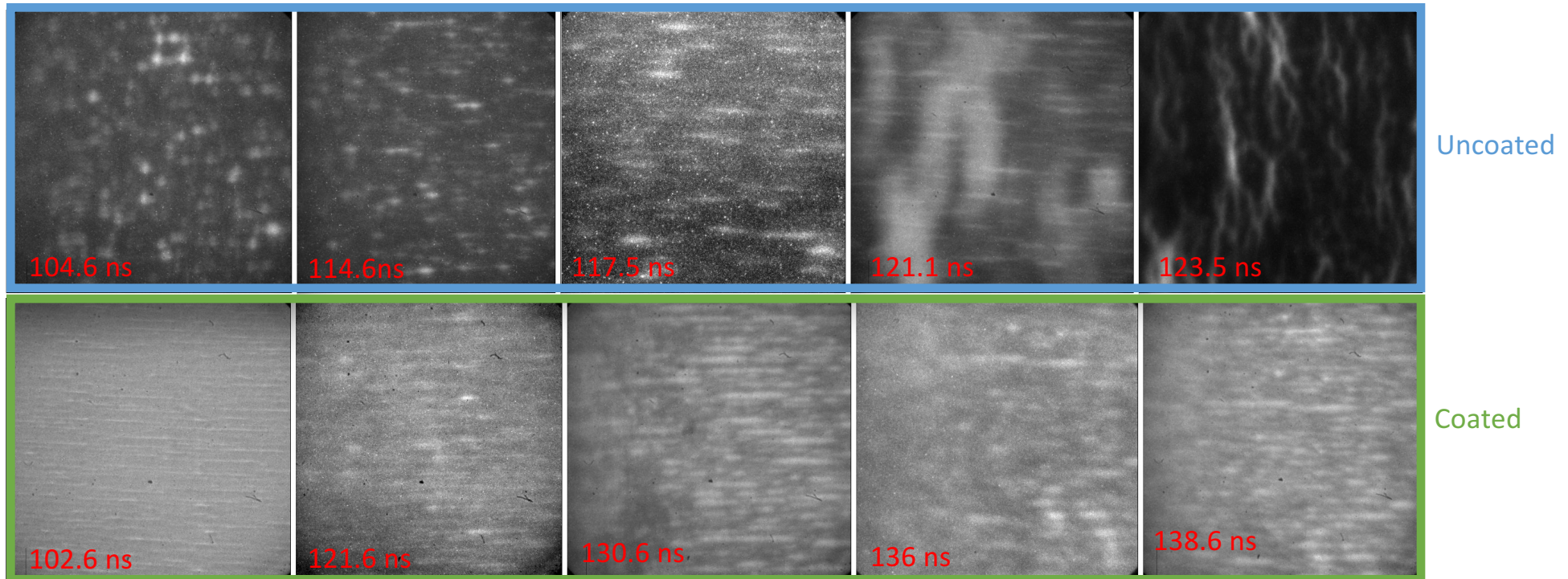
Then across 5  
coated here  
and 6 uncoated  
shots here



<sup>1</sup>Lindemuth (2010) <sup>2</sup>Raizer (1991)



# Dielectric Strongly Modifies Evolution of VIS

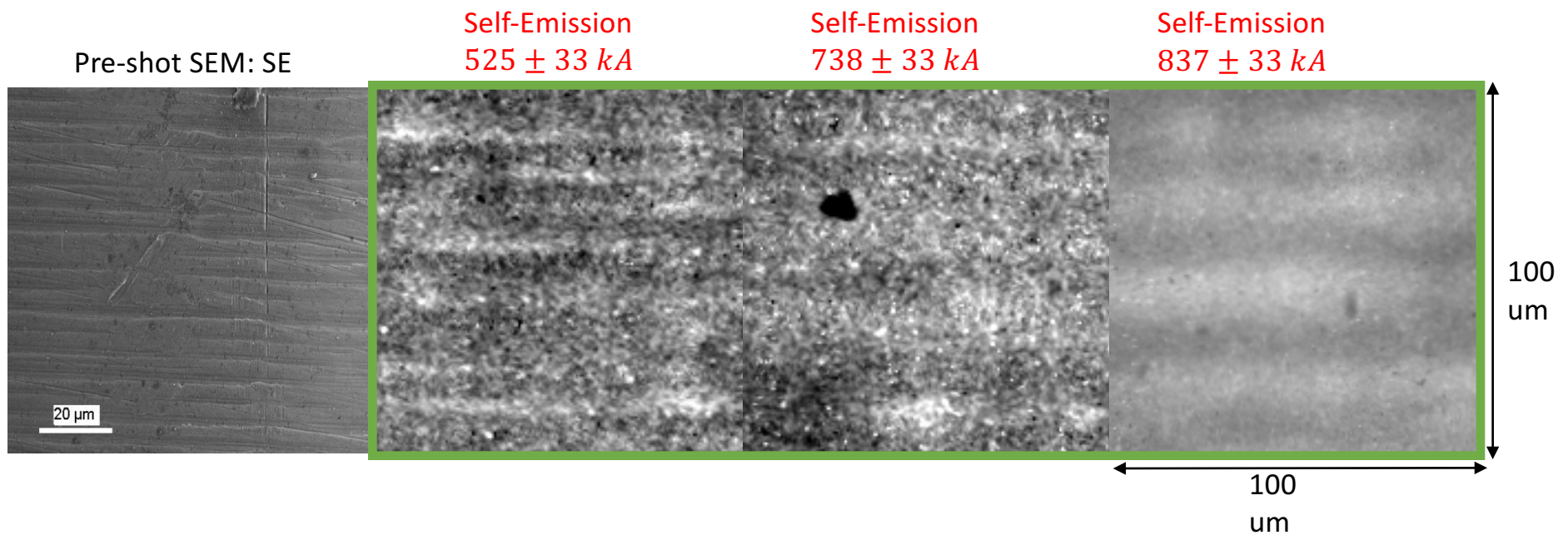


Uncoated display: dots --> strata --> filaments. Filamentary plasma emissions rapidly overwhelm strata that ALEGRA suggests grows underneath.

Coated display: strata throughout. CH load-averaged emissions are greater than uncoated load-averaged emissions until these uncoated loads form filaments.



# The coated relationship between machining and self-emission evolution is clear qualitatively



Plank's Law  
[W/m<sup>3</sup>/str]

Notch Filter  
[% Transmitted]

Solid Angle  
[str]

Conversion Factor  
[e<sup>-</sup>/s/A]

Gain Setting  
[counts/ e<sup>-</sup>]

MCP Gate  
[s]

Nikon & Barlow  
[% Transmitted]

$$R(\lambda, T) = \overbrace{SR(\lambda, T)}^{Plank's\ Law} \underbrace{P(\lambda)}_{Pellicle} \underbrace{N_f(\lambda)}_{Notch\ Filter} \underbrace{Q_E(\lambda)}_{Photocathode\ Quantum\ Efficiency} \underbrace{S_A}_{Solid\ Angle} \underbrace{E_A}_{Emitter\ Area} \underbrace{\hat{A}}_{Conversion\ Factor} \underbrace{r}_{ICCD\ Window, Debris\ Shield, Chamber\ Window} \underbrace{\hat{g}_a}_{Gain\ Setting} \underbrace{\hat{g}_t}_{MCP\ Gate} \underbrace{p_t}_{Nikon\ \&\ Barlow} \underbrace{O_{ldm}(\lambda)}_{Two\ Aluminum\ mirrors, AR\ coating\ and\ BK7\ glass} N_B(\lambda) / \underbrace{P_n}_{Number\ of\ Pixels}$$

Pellicle  
[% Transmitted]

Photocathode Quantum Efficiency  
[% = photo-e<sup>-</sup> / # photons  
~ A/W]

Emitter Area  
[m<sup>2</sup>]

ICCD Window,  
Debris Shield,  
Chamber Window  
[% Transmitted]

Parylene  
Transmission  
[% Transmitted]

Two Aluminum  
mirrors, AR coating  
and BK7 glass [%  
Transmitted].

Number of  
Pixels

$$r = 0.96^6$$

$$g_a = 339 \frac{\text{counts}}{e^-} \text{ SNL and } 498 \frac{\text{counts}}{e^-} \text{ UNR (typical)}$$

$$g_t = 2 \text{ ns for SNL and } 3.5 \text{ ns for UNR (typical)}$$

$$E_A = 600^2 \mu\text{m}^2$$

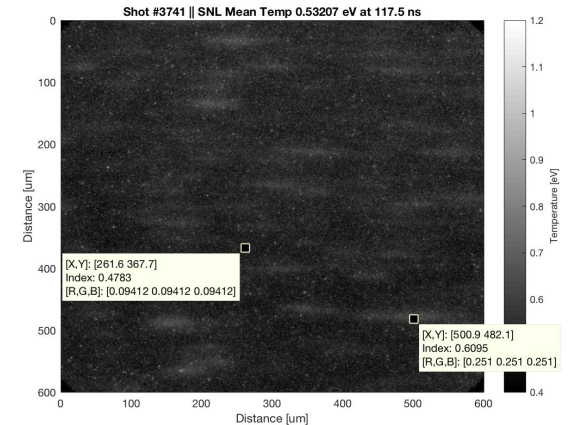
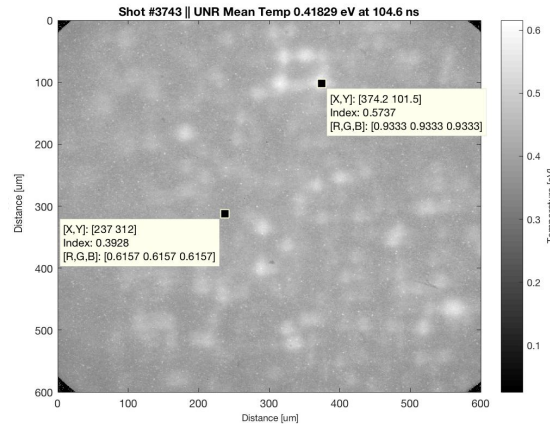
$$P_n = 1024^2$$

Note: the pellicle and quantum efficiencies will be different for SNL vs. UNR Cameras



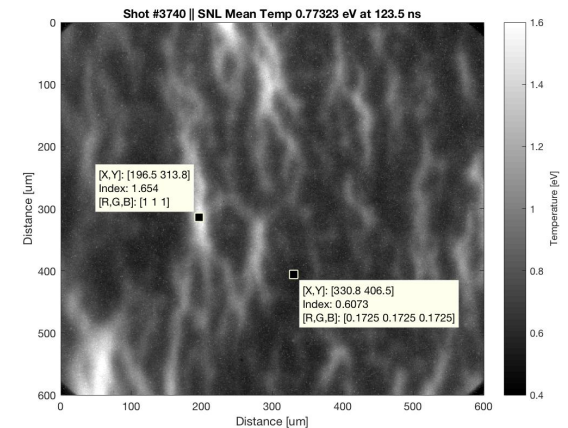
Sandia  
National  
Laboratories

# ICCD-Temp Maps :: Uncoated Loads



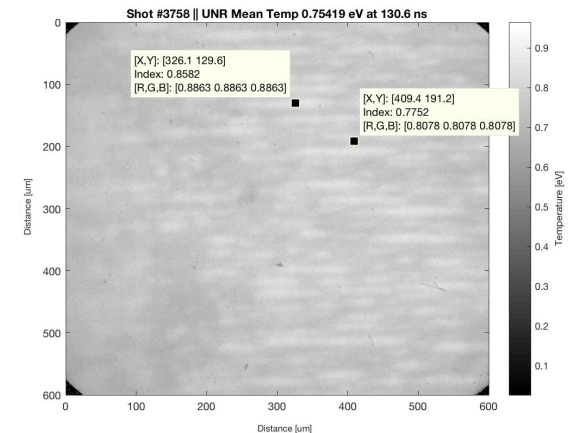
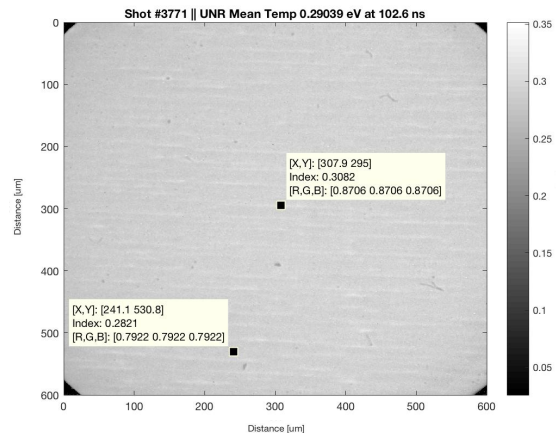
Time/Current

- Cameras disagree at  $> 0.8$  eV temperatures, which we believe is due to reliance on mfg. Specs. Both cameras agree that:
  - dots and strata are 0.1-0.2 eV hotter than background.
  - Dots/strata do not appear above 0.8 eV.
  - Filaments are only observed 0.6 eV and hotter.

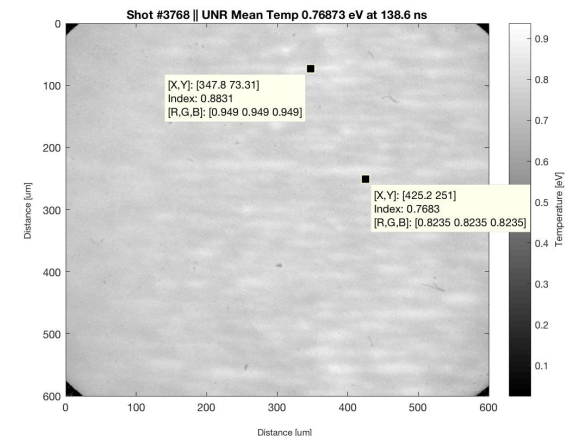




# ICCD-Temp Maps :: Coated Loads



Time/Current



- Strata appear with  $T_{BB} \sim 0.27 \text{ eV}$ , which is  $\sim 0.3 \text{ eV}$  cooler than hot spots on **uncoated loads** at the same, early time. The dielectric appears to suppress hot spot formation completely
- Filaments are not observed as late as our ICCD images have been taken, suggesting  $\partial\eta/\partial T$  does not change sign and therefore that plasma does not form.



# Summary

- We think **CH-coated loads** do not form plasma because:
  - Shadowgrams displays no appreciable MRT
  - Shadowgraph expansion speeds do not change near peak current
  - PDA never displays a sharp increase in VIS emissions.
  - Filaments are not observed.
- ETI persists for  $\sim 50$  ns, and remain highly (but perhaps decreasingly) azimuthally correlated. Suppression of hot spots is consistent with hydrodynamic tamping of ECI.
- Evidence suggests dielectric does not carry current.

Consistent  
with  
hydrodynamic  
tamp.





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